

EAST Search History

EAST Search History (Prior Art)

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S36	2	"20030186520"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/14 20:27
S37	1	"10589733"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/14 20:28
S38	3	resistivit same ((substrates wafers) with (cutting segmenting))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/14 20:30
S39	353	resistivity same ((substrates wafers) with (cutting segmenting))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/14 20:30
S40	0	resistivity same (((Fe iron) near (substrates wafers)) with (cutting segmenting))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/14 20:30
S41	1	temperature same (((Fe iron) near (substrates wafers)) with (cutting segmenting))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/14 20:31
S42	27	((((Fe iron) near (substrates wafers)) with (cutting segmenting))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/14 20:31

S43	1	((Fe near doped) near (substrates wafers)) with (cutting segmenting))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/14 20:33
S44	11	((Fe near doped) near (substrates wafers))) same resistivity	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/14 20:34
S45	14	("4292092" "4633030" "4846896" "5019177" "5266125" "5322572" "5389158" "5593901" "5616185" "5716459" "5769964" "5853497" "5897715" "6162987"). PN. OR ("6239354"). URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2009/11/14 20:35
S46	6	("4357180" "4676840"). PN. OR ("4929564"). URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2009/11/14 20:36
S47	8	("20030077870" "20030077870" "20030186520" "4673446" "4929564" "5164359" "5603765" "6022749" "6214708"). PN.	US-PGPUB; USPAT; USOCR	OR	ON	2009/11/14 20:38
S48	33	measuring near resistivity near (substrate wafer)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/19 16:27
S49	2900	measuring near resistivity	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/19 16:34
S50	770	((substrate wafer) with ("Fe")) with InP	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/19 16:34

S51	4	S49 and S50	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/19 16:34
S52	0	("2007/0190757").URPN.	USPAT	OR	ON	2009/11/19 16:35
S53	0	measuring near resistivity near (heating near temperature)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/19 17:04
S54	0	measuring near resistivity near (heating)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/19 17:04
S55	2	measuring near resistivity near (heating annealing)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/19 17:04
S56	232	measuring near resistivity same (heating annealing)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/19 17:04
S57	4	measuring near resistivity same(heating near temperature)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/19 17:05
S58	4	measuring near resistivity same (heating near temperature)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/19 17:05
S59	1128	resistivity same (heating near temperature)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/19 17:05

S60	0	S50 and S59	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/19 17:05
S61	21101	((substrate wafer) with InP)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/19 17:06
S62	8	S59 and S61	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/19 17:06
S63	0	adjuting near (heating near temperature)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/19 17:08
S64	0	adjuting near (heating)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/19 17:08
S65	80	((substrate wafer) with ("Fe")) with InP) with (epitaxial epitaxy)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/19 18:21
S66	3661	resistivity near temperature	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/19 18:22
S67	1	S65 and S66	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/19 18:22

S68	1419	resistivity near adjust\$3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/19 18:23
S69	0	S65 and S68	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/19 18:23
S70	11	heating near temperature near resistivity	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/19 18:25
S71	2	"20030186520"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/19 19:11
S72	66	measuring near resistivity same (room near temperature)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/19 19:34
S73	2	"6257760".pn.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/19 19:43
S74	2	"2002168856"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/19 20:54
S75	2	"20020168856"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/19 20:54

S76	16	"5057849"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/20 07:56
S77	14	"5057849"	US-PGPUB; USPAT; JPO	OR	ON	2009/11/20 07:56
S78	0	"jp5057849"	US-PGPUB; USPAT; JPO	OR	ON	2009/11/20 07:57

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